Se	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/750,845	KANG ET AL.	
Examiner	Art Unit	•
John S. Chu	1795	

	SEARCHED		
Class	Subclass	Date	Examiner
430	326	12/2007	Je.
430	191	1	
430	192		
430	193		
430	270.1		
427	57		
427	240		
427	241		
427	346	1	*

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
430	326,270.1	12/2001	3ºc
430	191,192	1	1
430	193		
427/57,24	40,241,346		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
UPDATED	12/2647	Jæ
	•	